Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,252	KIM ET AL.
Examiner	Art Unit
Anh T N Vo	2861

	SEAR	CHED	
Class	Subclass	Date	Examiner
mila	ter/se	and of	9/10

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
		ļ
	Í	1